

Abstract Submitted  
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**Nanomechanical Characterization Using PinPoint™ for Atomic Force Microscopy Applications** ARMANDO MELGAREJO, Engineer, Park Systems — Why use PinPoint™ Nanomechanical mode? PinPoint™ is an advance imaging mode developed by Park Systems, that acquires high-resolution topography and F/D data at each pixel of the entire scan area. With PinPoint™ mode, quantitative nanomechanical properties (i.e., modulus, adhesion, topography) can be obtained all at once. This presentation will cover PinPoints™ operation principle and the acquisition of nanomechanical properties through this method will be demonstrated using a Park Systems NX10 AFM.

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